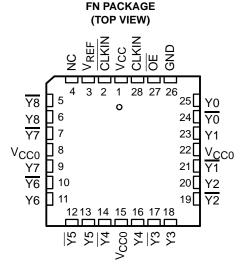
SCAS321F - SEPTEMBER 1993 - REVISED AUGUST 1996

- Low-Output Skew for Clock-Distribution Applications
- Differential Low-Voltage Pseudo-ECL (LVPECL)-Compatible Inputs and Outputs
- Distributes Differential Clock Inputs to Nine Differential Clock Outputs
- Output Reference Voltage, V_{REF}, Allows Distribution From a Single-Ended Clock Input
- Single-Ended LVPECL-Compatible Output Enable
- Packaged in Plastic Chip Carrier

description

The differential LVPECL clock-driver circuit distributes one pair of differential LVPECL clock inputs (CLKIN, $\overline{\text{CLKIN}}$) to nine pairs of differential clock (Y, $\overline{\text{Y}}$) outputs with minimum skew for clock distribution. It is specifically designed for driving $50-\Omega$ transmission lines.



NC - No internal connection

When the output-enable (\overline{OE}) is low, the nine differential outputs switch at the same frequency as the differential clock inputs. When \overline{OE} is high, the nine differential outputs are in static states (Y outputs are in the low state, \overline{Y} outputs are in the high state).

The V_{RFF} output can be strapped to the CLKIN input for a single-ended CLKIN input.

The CDC111 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

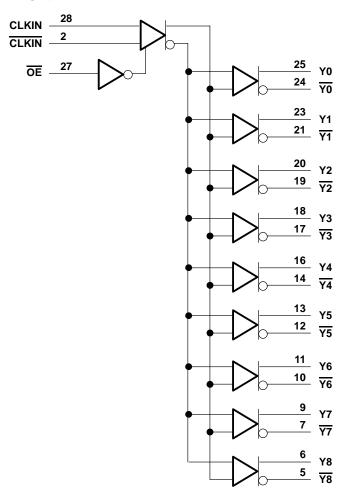
INPUTS			OUTPUTS		
CLKIN	CLKIN	OE	Yn	Υn	
Х	Х	Н	L	Н	
L	Н	L	L	Н	
Н	L	L	Н	L	
L	V_{REF}	L	L	Н	
Н	V_{REF}	L	Н	L	
V_{REF}	L	L	Н	L	
VREF	Н	L	L	Н	



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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, VO (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$)	–18 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	–18 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	–50 mA
Continuous current through V _{CC} or GND	\pm 80 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2)	525 mW
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 - 2. The maximum package power dissipation is calculated using a juction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002.



CDC111 1-LINE TO 9-LINE DIFFERENTIAL LVPECL CLOCK DRIVER

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recommended operating conditions (see Note 3)

			MIN	MAX	UNIT
VCC	Supply voltage		3	3.6	V
VIH High-level input volta	High level input voltage	V _{CC} = 3 V to 3.6 V	V _{CC} -1.165	V _{CC} -0.88	V
	riigii-ievei iriput voitage	V _{CC} = 3.3 V	2.135	2.420	V
V _{IL} Low-level input voltage	Low level input voltage	$V_{CC} = 3 V \text{ to } 3.6 V$		V _{CC} -1.475	V
	Low-level input voitage	V _{CC} = 3.3 V	1.49	1.825	V
TA	Operating free-air temperature		0	70	°C

NOTE 3: V_{CC} = V_{CCO}

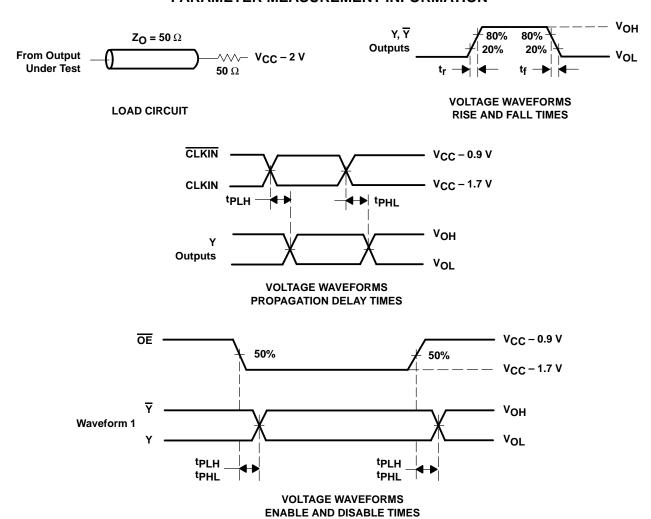
electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT	
VREF	V _{CC} = 3 V to 3.6 V	V _{CC} -1.38 V _{CC} -1.26		· v	
	V _{CC} = 3.3 V	= 3.3 V 1.92			
VOH	V _{CC} = 3 V to 3.6 V	V _{CC} -1.025	V _{CC} -0.88	٧	
	V _{CC} = 3.3 V	2.275	2.42		
W	V _{CC} = 3 V to 3.6 V	V _{CC} -1.81	V _{CC} -1.62	٧	
V _{OL}	V _{CC} = 3.3 V	1.49	1.68	V	
I _I	$V_1 = 2.4 \text{ V}, \qquad V_{CC} = 3.6 \text{ V}$		150	μΑ	
Icc	$I_{O} = 0,$ $V_{CC} = 3.6 \text{ V}$		80	mA	

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT
^t PLH	CLKIN, CLKIN	Y, \overline{Y}	450	600	nc
^t PHL			450	600	ps
^t PHL	ŌĒ	Y, \overline{Y}		900	ps
t _{sk(0)}		Y, $\overline{\overline{Y}}$		50	ps
t _{sk(pr)}		Y, \overline{Y}		150	ps
t _r		Y, $\overline{\overline{Y}}$	200	600	ps
tf		Y, \overline{Y}	200	600	ps

PARAMETER MEASUREMENT INFORMATION

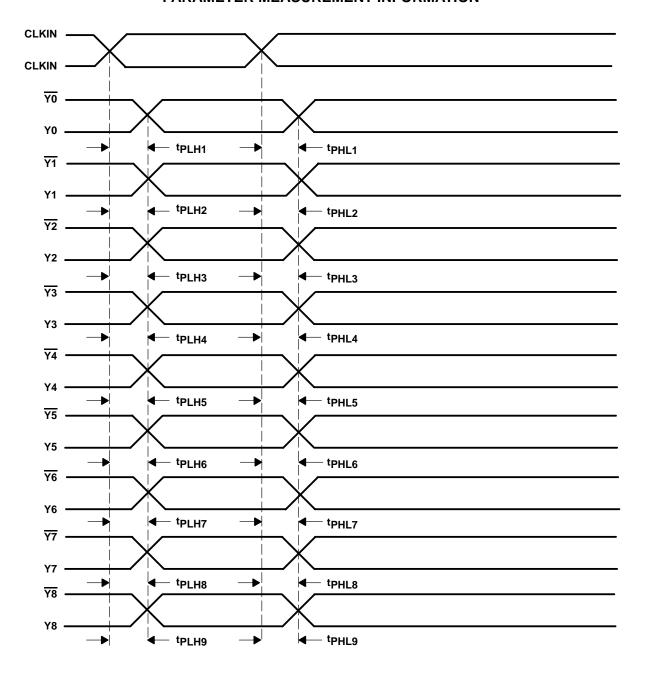


NOTES: A. All input pulses are supplied by generators having the following characteristics: PRR \leq 45 MHz, $Z_O = 50 \ \Omega$, $t_f \leq 1 \ ns$, $t_f \leq 1 \ ns$.

- B. Waveform 1 is for a \overline{Y} output with internal conditions such that the output is high except when disabled by the output control, and for a Y output with internal conditions such that the output is low except when disabled by the output control.
- C. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION



NOTES: A. Output skew, $t_{Sk(0)}$, is calculated as the greater of:

- The difference between the fastest and slowest tpLHn (n = 1, 2, . . . 9)
- The difference between the fastest and slowest t_{PHLn} (n = 1, 2, . . . 9)
- B. Process skew, t_{Sk(pr)}, is calculated as the greater of:

 The difference between the fastest and slowest t_{PLHn} (n = 1, 2, ... 9)

 The difference between the fastest and slowest t_{PHLn} (n = 1, 2, ... 9) across multiple devices

Figure 2. Waveforms for Calculation of $t_{sk(o)}$, $t_{sk(pr)}$



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